

United States Patent and Trademark Office

8h

UNITED STATES DEPARTMENT OF COMMERCE United States Patent and Trademark Office Address: COMMISSIONER FOR PATENTS P.O. Box 1450 Alexandria, Virginia 22313-1450 www.uspto.gov

APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/602,357	06/23/2003	Robert Benware	02-6301 81563	8900
75	590 09/23/2004		EXAMINER	
Leo J. Peters LSI Logic Corporation			RAYMOND, EDWARD	
MS D-106			ART UNIT	PAPER NUMBER
1551 McCarthy Blvd.			2857	
Milpitas, CA	95035		DATE MAILED: 09/23/2004	1

Please find below and/or attached an Office communication concerning this application or proceeding.

		- lhe
	Application No.	Applicant(s)
	10/602,357	BENWARE, ROBERT
Office Action Summary	Examiner	Art Unit
The MAIL INC DATE of this communication on	Edward Raymond	2857
The MAILING DATE of this communication ap Period for Reply	pears on the cover sheet with tr	ie corresponaence address
A SHORTENED STATUTORY PERIOD FOR REPL THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1. after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a rep - If NO period for reply is specified above, the maximum statutory period - Failure to reply within the set or extended period for reply will, by statute Any reply received by the Office later than three months after the mailine earned patent term adjustment. See 37 CFR 1.704(b).	136(a). In no event, however, may a reply b ly within the statutory minimum of thirty (30) will apply and will expire SIX (6) MONTHS e, cause the application to become ABAND	ne timely filed I days will be considered timely. If om the mailing date of this communication. ONED (35 U.S.C. § 133).
Status		
 1) □ Responsive to communication(s) filed on 23 J 2a) □ This action is FINAL. 2b) □ This 3) □ Since this application is in condition for allowated closed in accordance with the practice under the condition of the con	s action is non-final. ance except for formal matters,	
Disposition of Claims		
 4) ☐ Claim(s) 1-12 is/are pending in the application 4a) Of the above claim(s) is/are withdra 5) ☐ Claim(s) is/are allowed. 6) ☐ Claim(s) 1,3,5,7,9 and 11 is/are rejected. 7) ☐ Claim(s) 2,4,6,8,10 and 12 is/are objected to. 8) ☐ Claim(s) are subject to restriction and/or 	wn from consideration.	
Application Papers		
9)☐ The specification is objected to by the Examina 10)☒ The drawing(s) filed on 23 June 2003 is/are: a Applicant may not request that any objection to the Replacement drawing sheet(s) including the correct 11)☐ The oath or declaration is objected to by the E	a) accepted or b) objected or b) obj	See 37 CFR 1.85(a). s objected to. See 37 CFR 1.121(d).
Priority under 35 U.S.C. § 119		
12) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of: 1. Certified copies of the priority document 2. Certified copies of the priority document 3. Copies of the certified copies of the priority document application from the International Bureat * See the attached detailed Office action for a list	nts have been received. Its have been received in Appli Pority documents have been rec Bau (PCT Rule 17.2(a)).	cation No eived in this National Stage
Attachment(s) 1) ☑ Notice of References Cited (PTO-892)	4) ☐ Interview Sumn	nary (PTO-413)
 Notice of Draftsperson's Patent Drawing Review (PTO-948) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08 Paper No(s)/Mail Date 	Paper No(s)/Ma	

Application/Control Number: 10/602,357

Art Unit: 2857

DETAILED ACTION

Claim Rejections - 35 USC § 103

- 1. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 2. Claims 1, 3, 5, 7, 9, and 11 are rejected under 35 U.S.C. 103(a) as being unpatentable over Verhelst et al. in view of Cole, Jr. et al. Verhelst et al. teach a method of screening defects comprising steps of (a) measuring a quiescent current at a first supply voltage for each of a plurality of devices (Claims 1 and 7: see col. 4, lines 30-38) and (b) measuring a quiescent current at a second supply voltage for each of the plurality of devices (Claims 1 and 7: see col. 4, lines 30-38).

Verhelst et al. teach a method wherein the first supply voltage is a nominal supply voltage of the plurality of devices (Claims 3 and 9: see col. 4, lines 55-64).

Verhelst et al. teach a method wherein the quiescent current is measured at the first supply voltage for multiple stop points in a test pattern (Claims 5 and 11: see col. 6, lines 1-13: The Examiner notes that the measurements at the multiple transistors is equivalent to multiple stop points in a test pattern).

Verhelst et al. does not teach (c) generating a plot of the quiescent current measured at the first supply voltage vs. the quiescent current measured at the second supply voltage for each of the plurality of devices; (d) determining a range of intrinsic variation of quiescent current in the plot; and (e) identifying any of the plurality of

Art Unit: 2857

devices corresponding to a measurement plotted outside the range of intrinsic variation as defective. Cole, Jr. et al. teach (c) generating a plot of the quiescent current measured at the first supply voltage vs. the quiescent current measured at the second supply voltage for each of the plurality of devices (Claims 1 and 7: see Figure 3 and also col. 8, lines 20-51: The Examiner notes that first supply voltage and second supply is plotted); (d) determining a range of intrinsic variation of quiescent current in the plot (Claims 1 and 7: see col. 10, lines 1-16); and (e) identifying any of the plurality of devices corresponding to a measurement plotted outside the range of intrinsic variation as defective (Claims 1 and 7: see col. 4, lines 47-63). It would have been obvious to the person having ordinary skill in the art at the time the invention was made to modify Verhelst et al. to use a plot to find the range of variation of quiescent current to identify defects, as taught by Cole, Jr. et al., because this would allow for adequately indicating whether a VLSI circuit under test is free from defects (see col. 1, lines 35-52).

Allowable Subject Matter

3. Claims 2, 4, 6, 8, 10, and 12 are objected to as being dependent upon a rejected base claim, but would be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.

Contact Information

4. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Edward Raymond whose telephone number is 571-272-2221. The examiner can normally be reached on Monday through alternating Friday between 8:00 AM and 5:30 PM.

Application/Control Number: 10/602,357 Page 4

Art Unit: 2857

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Marc Hoff can be reached on 571-272-2216. The fax phone numbers for the organization where this application or proceeding is assigned are 571-273-2221 for regular communications and 571-272-1562 for After Final communications.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is 703-308-1782.

September 17, 2004 Edward Raymond Patent Examiner Art Unit 2857 Edward Raymond
Patent Examiner